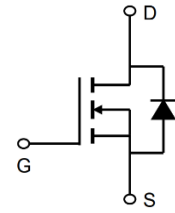


60V N-Channel Enhancement Mode MOSFET

Description

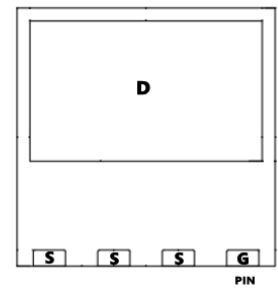
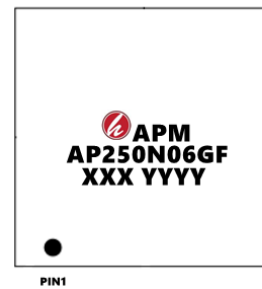
The AP250N06GF uses advanced **APM-SGT II** technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 10V. This device is suitable for use as a Battery protection or in other Switching application.



General Features

$V_{DS} = 60V$ $I_D = 250A$

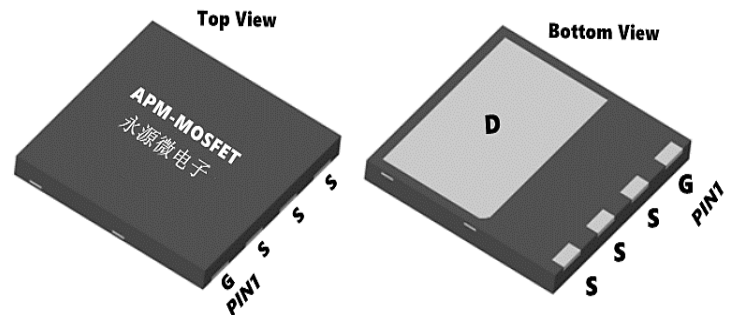
$R_{DS(ON)} < 2.7m\Omega$ @ $V_{GS}=10V$ (Type: 1.9m Ω)



Application

Battery protection

UPS



Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP250N06GF	DFN8X8-4L	AP250N06GF XXX YYYY	5000

Absolute Maximum Ratings ($T_C=25^\circ C$ unless otherwise noted)

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	60	V
V_{GS}	Gate-Source Voltage	± 20	V
$I_D @ T_C=25^\circ C$	Continuous Drain Current ^{1,6}	250	A
$I_D @ T_C=100^\circ C$	Continuous Drain Current ^{1,6}	140	A
IDM	Pulsed Drain Current ²	240	A
EAS	Single Pulse Avalanche Energy ³	585	mJ
IAS	Avalanche Current	55	A
$P_D @ T_C=25^\circ C$	Total Power Dissipation ⁴	168	W
TSTG	Storage Temperature Range	-55 to 150	$^\circ C$
T_J	Operating Junction Temperature Range	-55 to 150	$^\circ C$
$R_{\theta JA}$	Thermal Resistance Junction-Ambient ¹	12	$^\circ C/W$
$R_{\theta JC}$	Thermal Resistance Junction-Case ¹	1.5	$^\circ C/W$

60V N-Channel Enhancement Mode MOSFET

Electrical Characteristics (T_J=25°C, unless otherwise noted)

Symbol	Parameter	Test Conditions	Min	Type	Max	Unit
V(BR)DSS	Drain-Source Breakdown Voltage	V _{GS} = 0V, I _D = 250μA	60	66	-	V
IGSS	Gate-body Leakage Current	V _{DS} = 0V, V _{GS} = ±20V	-	-	±100	nA
IDSS T _J =25°C	Zero Gate Voltage Drain Current	V _{DS} = 60V, V _{GS} = 0V	-	-	1	μA
IDSS T _J =100°C	Zero Gate Voltage Drain Current		-	-	100	
VGS(th)	Gate-Threshold Voltage	V _{DS} = V _{GS} , I _D = 250μA	2.0	2.8	4.0	V
RDS(on)	Drain-Source On-Resistance ⁴	V _{GS} = 10V, I _D = 20A	-	1.9	2.7	mΩ
gfs	Forward Transconductance ⁴	V _{DS} = 5V, I _D = 20A	-	78	-	S
Ciss	Input Capacitance	V _{DS} = 30V, V _{GS} = 0V, f = 1MHz	-	5245	-	pF
Coss	Output Capacitance		-	1090	-	
Crss	Reverse Transfer Capacitance		-	25	-	
RG	Gate Resistance	f = 1MHz	-	2.2	-	Ω
Q _g	Total Gate Charge	V _{GS} = 10V, V _{DS} = 30V, I _D = 20A	-	72.5	-	nC
Q _{gs}	Gate-Source Charge		-	19.5	-	
Q _{gd}	Gate-Drain Charge		-	14	-	
td(on)	Turn-on Delay Time	V _{GS} = 10V, V _{DD} = 30V, R _G = 3Ω, I _D = 20A	-	26.5	-	ns
t _r	Rise Time		-	15	-	
td(off)	Turn-off Delay Time		-	73	-	
t _f	Fall Time		-	18	-	
trr	Body Diode Reverse Recovery Time	I _F = 20A, dI/dt = 100A/μs	-	25	-	ns
Qrr	Body Diode Reverse Recovery Charge		-	90	-	nC
VSD	Diode Forward Voltage ⁴	I _S = 20A, V _{GS} = 0V	-	-	1.2	V
IS	Continuous Source Current T _C =25°C	-	-	-	125	A

Note :

- 1、 The data tested by surface mounted on a 1 inch 2 FR-4 board with 2OZ copper.
- 2、 The data tested by pulsed , pulse width .The EAS data shows Max. rating .
- 3、 The power dissipation is limited by 175°C junction temperature
- 4、 EAS condition: T_J=25°C, V_{DD}=48V, V_G=10V, R_G=25Ω, L=0.1mH, I_{AS}= 55A
- 5、 The data is theoretically the same as ID and IDM , in real applications , should be limited by total power dissipation.

Typical Characteristics

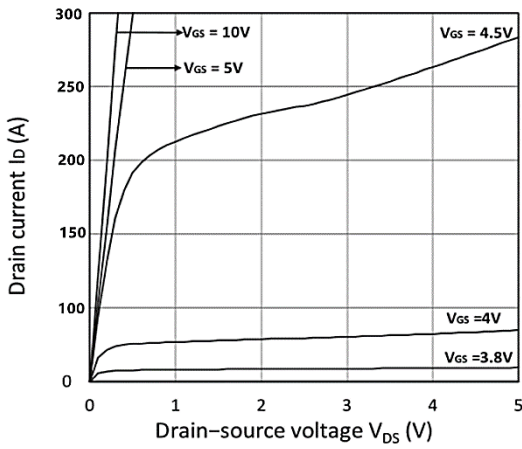


Figure 1. Output Characteristics

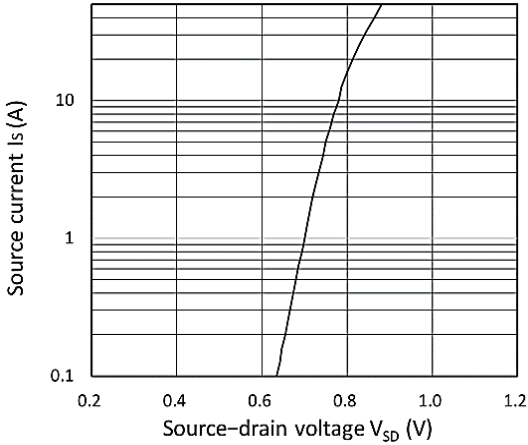


Figure 3. Forward Characteristics of Reverse

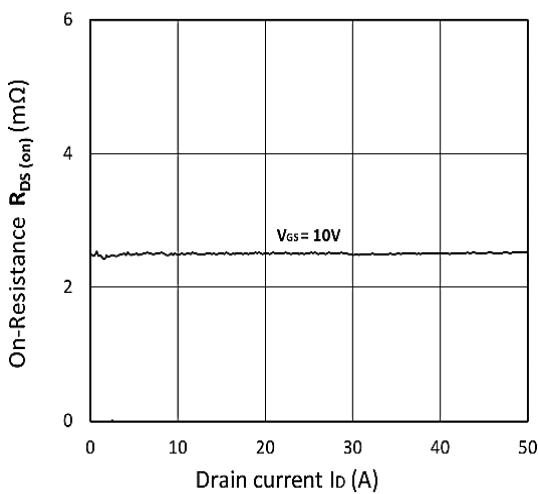


Figure 5. $R_{DS(on)}$ vs. I_D

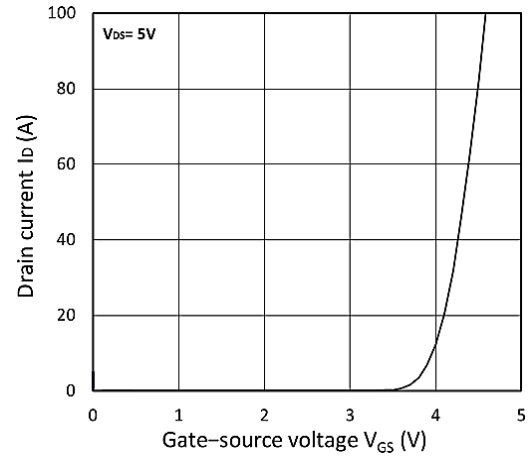


Figure 2. Transfer Characteristics

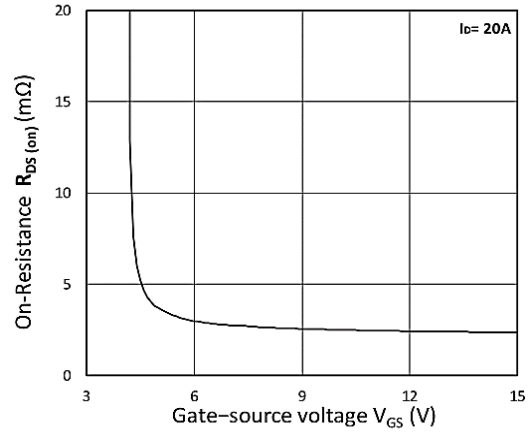


Figure 4. $R_{DS(on)}$ vs. V_{GS}

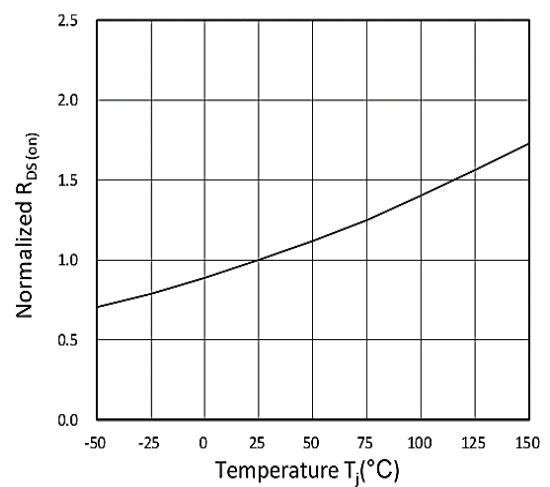


Figure 6. Normalized $R_{DS(on)}$ vs. Temperature

60V N-Channel Enhancement Mode MOSFET

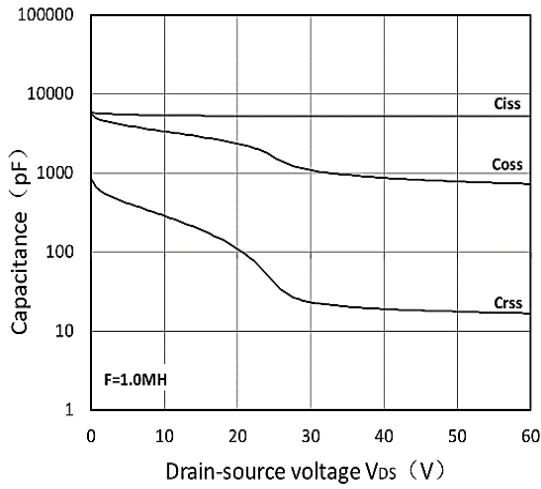


Figure 7. Capacitance Characteristics

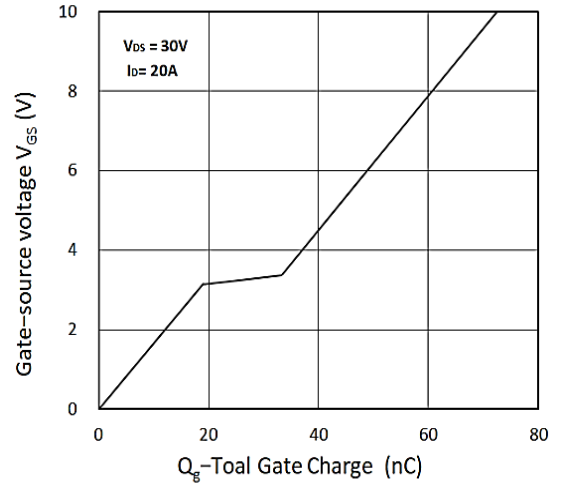


Figure 8. Gate Charge Characteristics

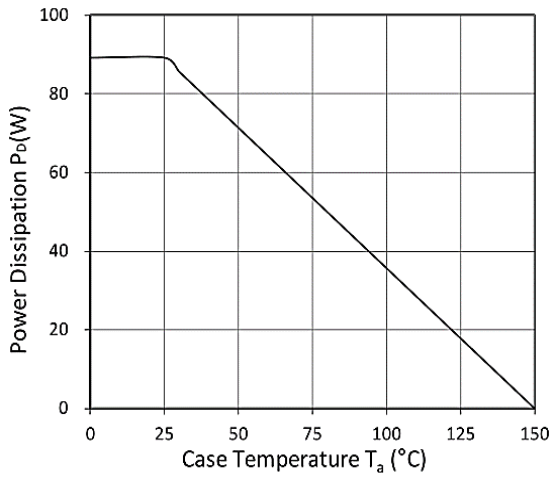


Figure 9. Power Dissipation

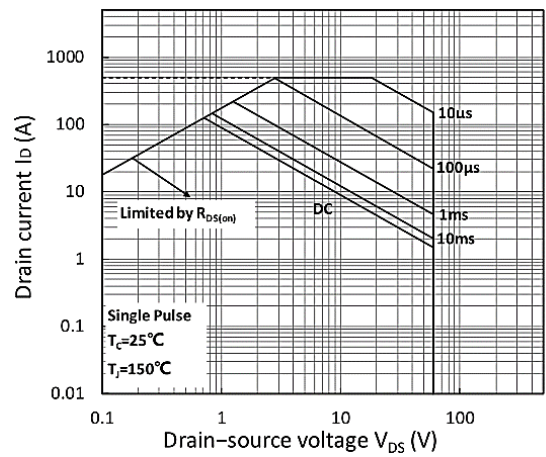


Figure 10. Safe Operating Area

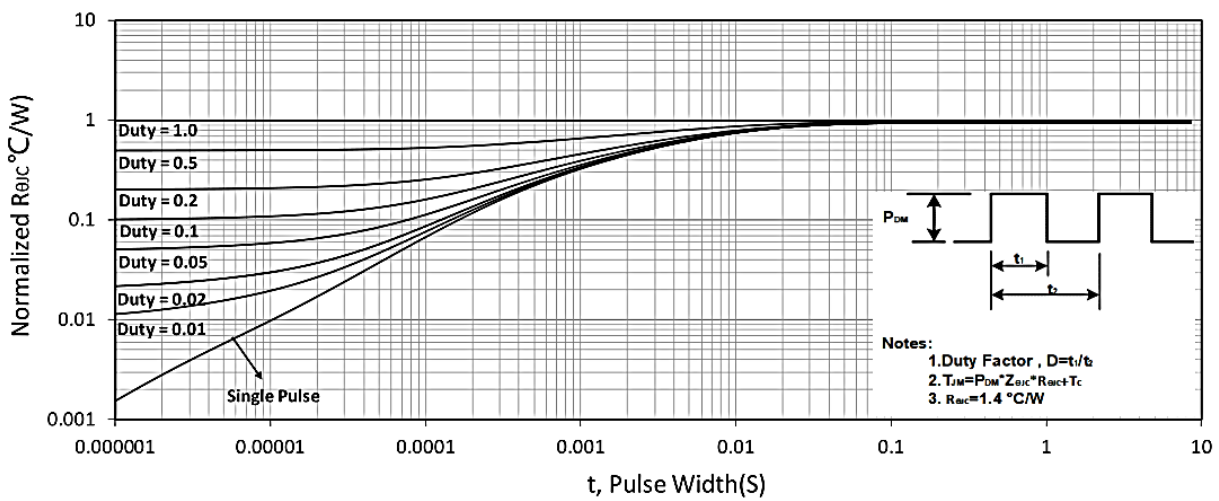
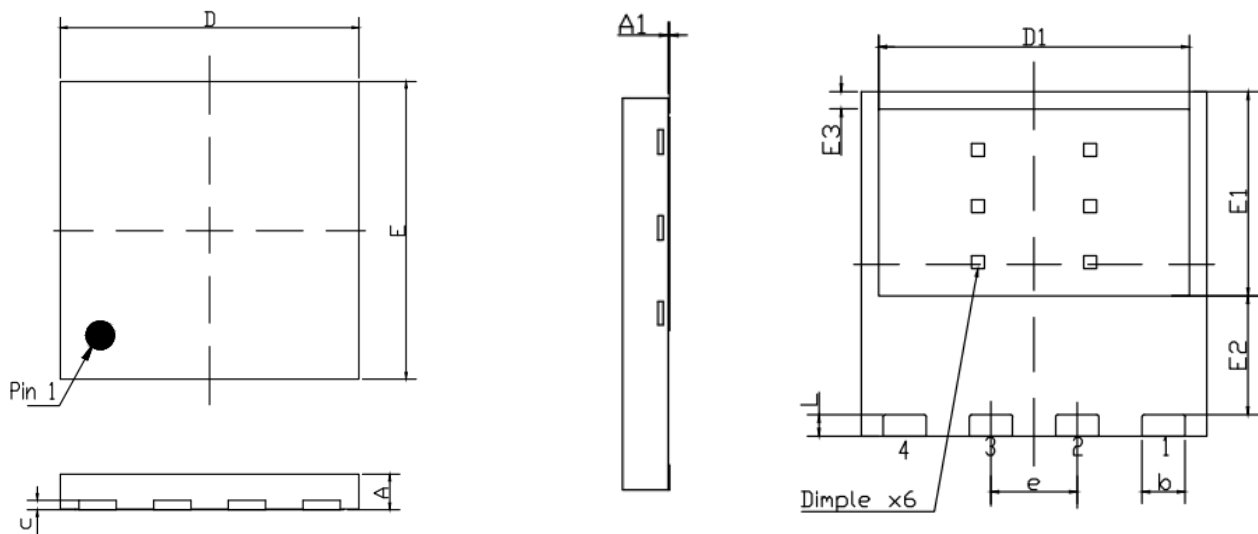


Figure 11. Normalized Maximum Transient Thermal Impedance

Package Mechanical Data-DFN8*8-4L



Symbols	Dimension in mn			Dimension in inches		
	Min	Nom	Max	Min	Nom	Max
A	0.800	0.850	1.10	0.031	0.033	0.043
A1	---	---	0.050	----	----	0.002
D	7.900	8.000	8.100	0.311	0.315	0.319
D1	7.10	7.20	7.30	0.279	0.283	0.287
E	7.900	8.000	8.100	0.311	0.315	0.319
E1	4.65	4.75	4.85	0.183	0.187	0.191
E2	2.65	2.75	2.85	0.104	0.108	0.112
E3	0.30	0.40	0.50	0.012	0.016	0.020
b	0.900	1.000	1.10	0.035	0.039	0.043
e	2.00 BSC			0.079 BSC		
c	0.15	0.25	0.35	0.006	0.010	0.014
L	0.40	0.50	0.60	0.016	0.020	0.024

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Edition	Date	Change
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